

**P1.1 AlGaN channel High Electron Mobility Transistors grown by NH<sub>3</sub>-MBE on Silicon substrates**

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**P1.3 AlScN alloys as pseudo-substrate for InGaN**

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**P1.5 Empirical Study of the Impact of Process Deviations on Structure and Performance of MIR-QCL for Volume Production**

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**P1.11 Growth and optimization of N-polar GaN epilayers on silicon substrates using ammonia-MBE and a hybrid NbN/AlN buffer layer**

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**P1.13 Growth of InAlN/NbN Heterostructures in Indium-rich Conditions by Plasma Assisted MBE**

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**P1.15 High Resolution Temperature Mapping of Intentionally Induced Thermal Gradients on GaSb Wafers during Growth**

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**P1.17 Influence of growth temperature and scandium concentration on the oxidation of ScAlN films grown by molecular beam epitaxy**

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**P1.19 Investigation of the effect of GaAs substrate orientations and doping on the electrical and optical properties of InGaP solar cell structures**

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**P1.21 Metal-Modulated Growth of Cubic, Red Emitting InGaN Layers and Self-Assembled InGaN/GaN Quantum Wells by Molecular Beam Epitaxy**

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**P1.23 Photoluminescence investigation of the annealing effects on GaAsBi quantum wells with parabolic AlGaAs barriers**

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**P1.25 Production of mm-Wave epiwafers of GaN on Si grown by NH<sub>3</sub>-MBE**

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**P1.27 Short wavelength infrared avalanche photodiode beyond 2.0 μm based on InGaAs/GaAsSb superlattice as the absorber**

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**P1.29 Silicon epitaxy using trisilane**

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**P1.31 Automated growth of DBR supervised by in-situ spectral reflectance measurement**

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**P1.33 Key Points of Compound Semiconductor Material Evaluation by High resolution XRD**

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**P1.35 Manufacturing of Three Terminal Heterojunction Bipolar Solar Cells based on AlGaAs grown by MBE**

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**P1.37 NIR Diode Emitters for Applications in Biophotonics**

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**P1.39 Progress towards closed cycle AI controlled MBE systems**

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**P1.41 Growth and optical properties of  $\text{Al}_{1-x}\text{Ga}_x\text{As0.56Sb0.44}$  on InGaAs/InP**

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**P1.43 In-situ measurement of AlAs growth rate by magnification inferred curvature method**

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**P1.45 In situ control of GaN growth rate in nitrogen limited regime**

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